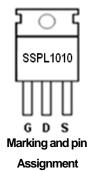


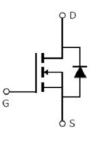
Main Product Characteristics:

V _{DSS}	100V
R _{DS} (on)	8.9mohm(typ.)
I _D	88A ①



TO220





Schematic diagram

Features and Benefits:

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description:

These N-Channel enhancement mode power field effect transistors are produced using silikron proprietary MOSFET technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	88 ①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	63 ①	Α
I _{DM}	Pulsed Drain Current ②	352	
D @TC 25%C	Power Dissipation ③	245	W
P _D @TC = 25°C	Linear Derating Factor	1.63	W/°C
V _{DS}	Drain-Source Voltage	100	V
V _{GS} Gate-to-Source Voltage		± 20	V
E _{AS} Single Pulse Avalanche Energy @ L=0.14mH		700	mJ
I _{AS}	Avalanche Current @ L=0.14mH	100	Α
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	_	0.61	°C/W
D	Junction-to-ambient (t $ \leqslant 10 \mathrm{s}) \oplus$	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	100	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D	Static Drain-to-Source on-resistance	_	8.9	10	m0	V _{GS} =10V,I _D =58A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	18.4	_	mΩ	T _J = 125°C
V	Cata threshold voltage	2	_	4	V	$V_{DS} = V_{GS}$, $I_D = 150\mu A$
$V_{GS(th)}$	Gate threshold voltage		2.09	_	V	T _J = 125°C
I	Drain to Source leakage ourrent		_	1	μA	$V_{DS} = 100V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current		_	50	μΑ	T _J = 125°C
	Cata to Source forward lookage	_	_	100	n A	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage	-100	_	_	nA	V _{GS} = -20V
Qg	Total gate charge	_	99.6	_		I _D = 120A,
Q _{gs}	Gate-to-Source charge	_	26.7	_	nC	V _{DS} =60V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	35.7	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	19.2	_		V _{GS} =10V, V _{DD} =68V,
tr	Rise time	_	20.5	_	nS	$R_L=1.17\Omega$,
t _{d(off)}	Turn-Off delay time	_	45.4	_	113	R _{GEN} =4.1Ω
tf	Fall time	_	7.2	_		I _D =58A
C _{iss}	Input capacitance	_	5530	_		V _{GS} = 0V
Coss	Output capacitance	_	440	_	pF	V _{DS} = 50V
C _{rss}	Reverse transfer capacitance	_	17	_		f =1MHz

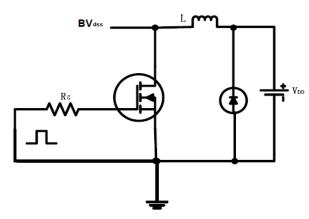
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		_	88	А	MOSFET symb
	(Body Diode)	_				showing the
I _{SM}	Pulsed Source Current		_	352	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.87	1.5	V	I _S =58A, V _{GS} =0V, T _J = 25°C
t _{rr}	Reverse Recovery Time	_	62.4	_	nS	$T_J = 25^{\circ}C$, $I_F = 58A$, $di/dt =$
Q _{rr}	Reverse Recovery Charge	_	186.2	_	nC	100A/µs

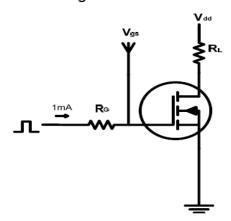


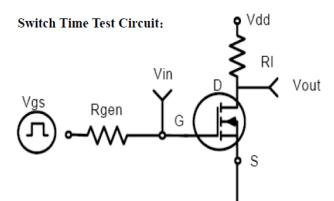
Test circuits and Waveforms

EAS test circuits:

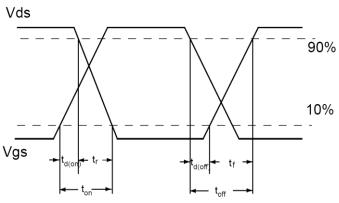


Gate charge test circuit:





Switch Waveforms:



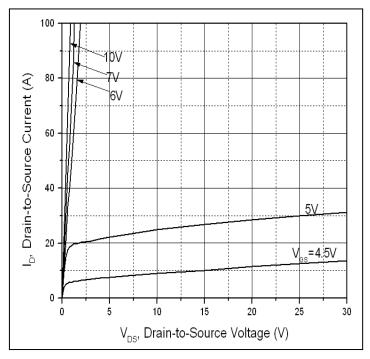
Version: 1.0

Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =175°C.



Typical electrical and thermal characteristics



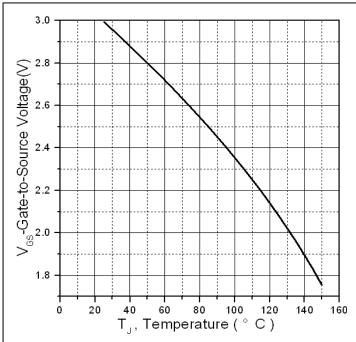


Figure 1: Typical Output Characteristics

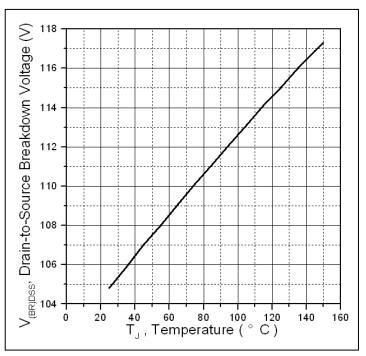


Figure 3. Drain-to-Source Breakdown Voltage vs.
Temperature

Figure 2. Gate to source cut-off voltage

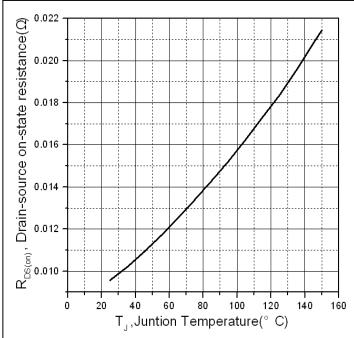
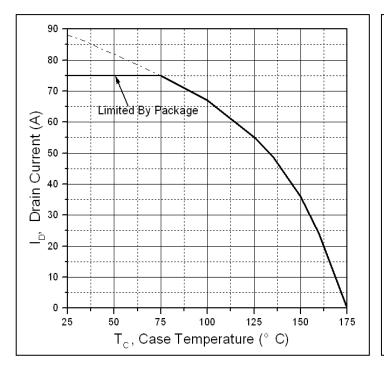


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



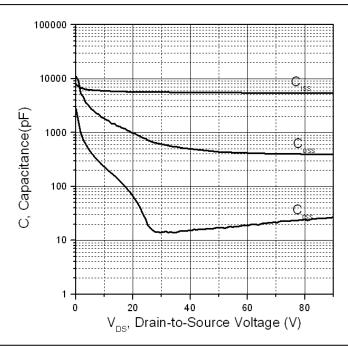


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

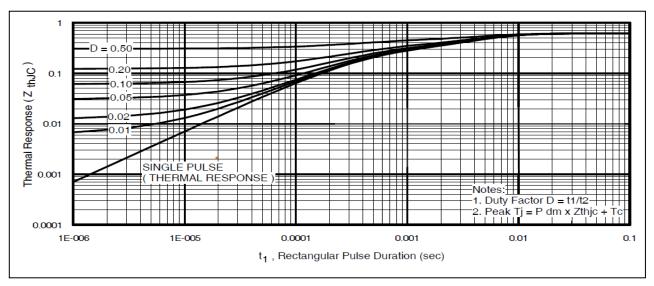
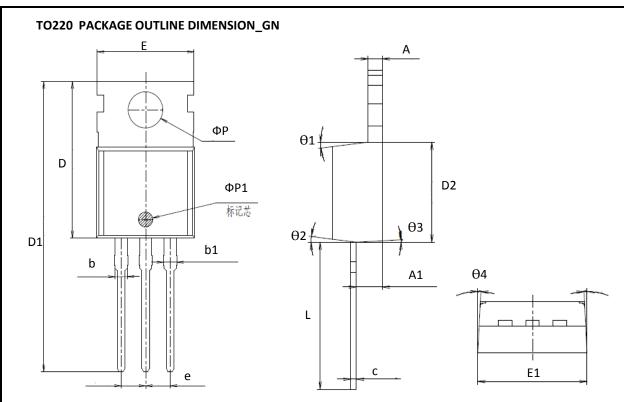


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Symbol	Dime	nsion In Millin	neters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
Α	-	1.300	-	-	0.051	-	
A1	2.200	2.400	2.600	0.087	0.094	0.102	
b	-	1.270	-	-	0.050	-	
b1	1.270	1.370	1.470	0.050	0.054	0.058	
С	-	0.500	-	-	0.020	-	
D	-	15.600	-	-	0.614	-	
D1	-	28.700	-	-	1.130	-	
D2	-	9.150	-	-	0.360	-	
Е	9.900	10.000	10.100	0.390	0.394	0.398	
E1	-	10.160	-	-	0.400	-	
ΦР	-	3.600	-	-	0.142	-	
ФР1		1.500		0.059			
е		2.54BSC			0.1BSC		
L	12.900	13.100	13.300	0.508	0.516	0.524	
Θ1	-	7 ⁰	-	-	7 ⁰	-	
Θ2	-	7 ⁰	-	-	7 ⁰	-	
Θ3	-	3 ⁰	-	5 ⁰	7 ⁰	90	
Θ4	-	3 ⁰	-	1 ⁰	3 ⁰	5 ⁰	





Ordering and Marking Information

Device Marking: SSPL1010

Package (Available)
TO220
Operating Temperature Range
C: -55 to175 °C

Devices per Unit

Package Type	Units/ Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =125℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			





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Customer Service

Worldwide Sales and Service:

Sales@silikron.com

Technical Support:

Technical@silikron.com

Suzhou Silikron Semiconductor Corp.

11A, 428 Xinglong Street, Suzhou Industrial Park, P.R.China

TEL: (86-512) 62560688 FAX: (86-512) 65160705 E-mail: Sales@silikron.com